

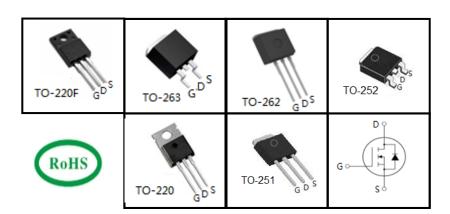
650V Super-Junction Power MOSFET

FEATURES

- $\bullet \quad \text{Very low FOM R}_{\text{DS(on)}} \times \text{Q}_{\text{g}} \\$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



Device Marking and Package Information						
Device TPA65R600C TPB65R600C TPC65R600C TPD65R600C TPP65R600C TPU65R600C						
Package	TO-220F	TO-263	TO-262	TO-252	TO-220	TO-251
Marking	65R600C	65R600C	65R600C	65R600C	65R600C	65R600C

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted						
Dougranton		Complete	Value		l lmit	
Parameter		Symbol	TO-220, TO-251, TO-252 TO-262, TO-263	TO-220F	Unit	
Drain-Source Voltage (V _{GS} =	· 0V)	$V_{\rm DSS}$	650		V	
$T_{\rm C} = 25^{\circ}{\rm C}$		-	7		А	
Continuous Drain Current	$T_{\rm C} = 100^{\rm o}{\rm C}$	I _D	4.2			
Pulsed Drain Current (note1)		I _{DM}	21		Α	
Gate-Source Voltage		V_{GSS}	±30		V	
Single Pulse Avalanche Ene	rgy (note2)	E _{AS}	162		mJ	
Avalanche Current	(note1)	I _{AS}	1.4		А	
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50		V/ns	
Reverse diode dv/dt, $V_{DS} = 0480V$, $I_{SD} \le I_{D}$		dv/dt	15		V/ns	
Power Dissipation (T _C = 25°C)		P _D	63	28	W	
Operating Junction and Store	age Temperature Range	T _J , T _{stg}	-55~+150		°C	

Thermal Resistance					
		Value			
Parameter	Symbol	TO-220, TO-251, TO-252 TO-262, TO-263	TO-220F	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	2.0	4.5	°C/W	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	80	90/88	



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Parameter	Symbol Test Conditions		Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650			V
Zoro Coto Voltago Drain Current		$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	^
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	μA
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V
Drain-Source On-Resistance (Note3)	R _{DS(on)}	$V_{GS} = 10V, I_{D} = 3A$		0.56	0.62	Ω
Forward Transconductance (Note3)	g _{fs}	$V_{DS} = 10V, I_{D} = 3A$		5		S
Dynamic						
Input Capacitance	C _{iss}	$V_{GS} = 0V,$ $V_{DS} = 50V,$ f = 1.0MHz		584		pF
Output Capacitance	C _{oss}			33		
Reverse Transfer Capacitance	C _{rss}			3		
Total Gate Charge	Q_g			14.5		
Gate-Source Charge	Q_{gs}	$V_{DD} = 520V, I_{D} = 7A, V_{GS} = 10V$		3		nC
Gate-Drain Charge	Q_{gd}			5.2		1
Turn-on Delay Time	t _{d(on)}			39		
Turn-on Rise Time	t _r	$V_{DD} = 400V, I_{D} = 7A,$		25		
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		100		ns
Turn-off Fall Time	t _f			18		
Drain-Source Body Diode Characteris	stics					
Continuous Body Diode Current	Is	T 0500			7	۸
Pulsed Diode Forward Current	I _{SM}	$T_C = 25^{\circ}C$			21	Α
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 7A$, $V_{GS} = 0V$		0.9	1.2	V
Reverse Recovery Time	t _{rr}			250		ns
Reverse Recovery Charge	Q _{rr}	$V_R = 480V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		2.1		μC
Peak Reverse Recovery Current	I _{rrm}	αι _τ , αι = 100/ 1 μυ		16		Α

Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. I_{AS} = 1.4A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 1%

Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

Figure 1. Output Characteristics

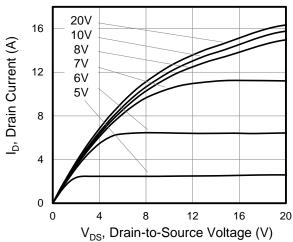


Figure 2. Transfer Characteristics

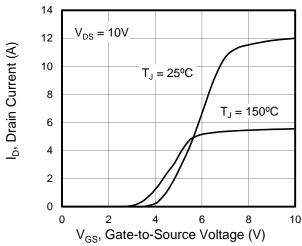


Figure 3. On-Resistance vs. Drain Current

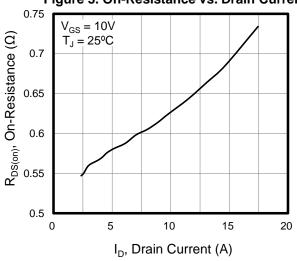


Figure 4. Capacitance

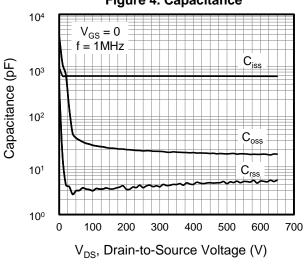


Figure 5. Gate Charge

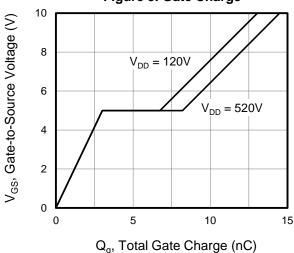
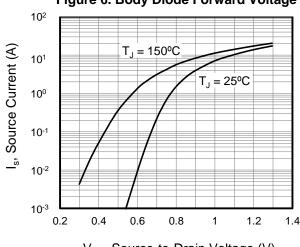


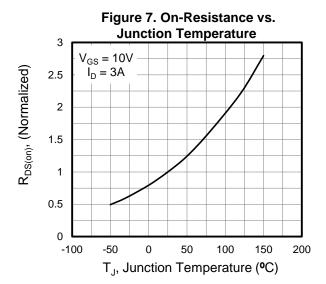
Figure 6. Body Diode Forward Voltage



V_{SD}, Source-to-Drain Voltage (V)



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted



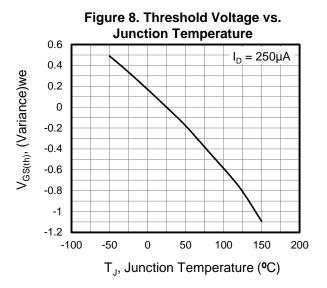
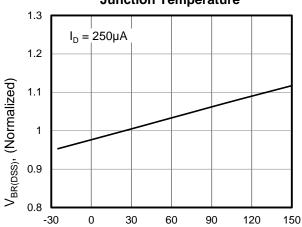


Figure 9. Breakdown voltage vs. Junction Temperature



T_J, Junction Temperature (°C)



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

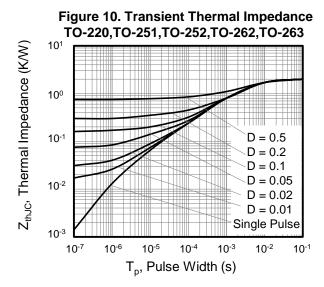


Figure 12. Safe operation area for

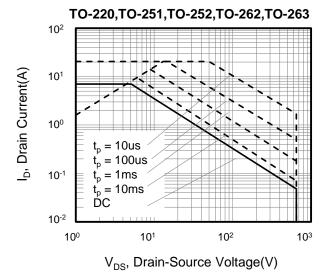


Figure 11. Transient Thermal Impedance TO-220F

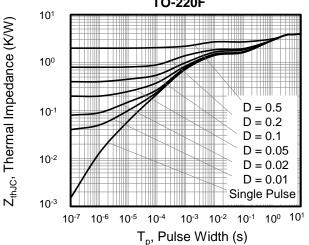
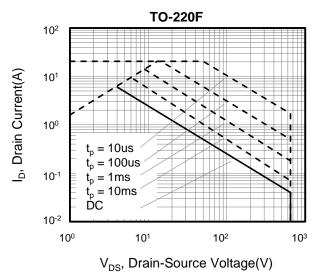


Figure 13. Safe operation area for



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Figure A: Gate Charge Test Circuit and Waveform

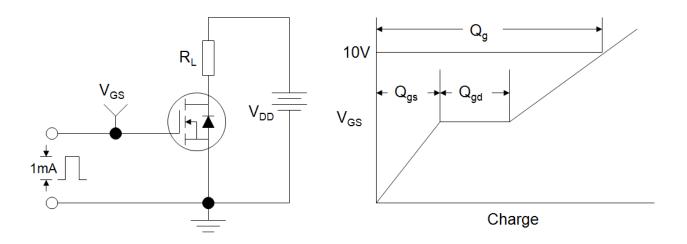


Figure B: Resistive Switching Test Circuit and Waveform

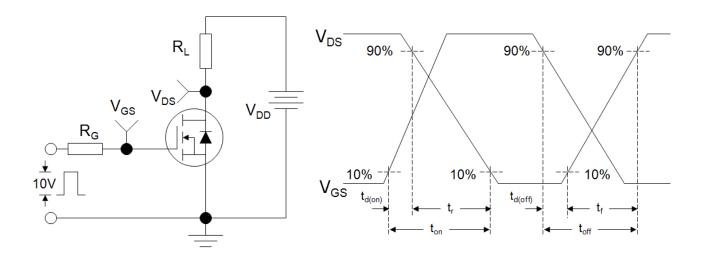
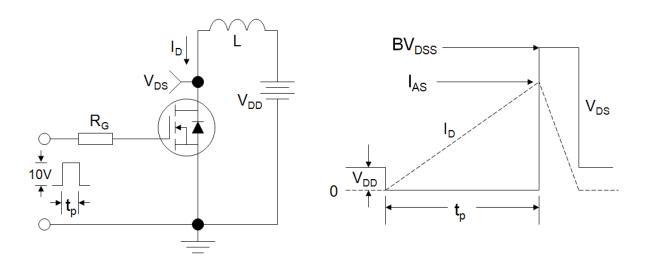
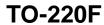


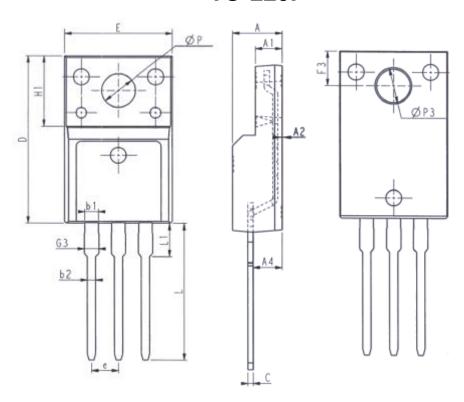
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



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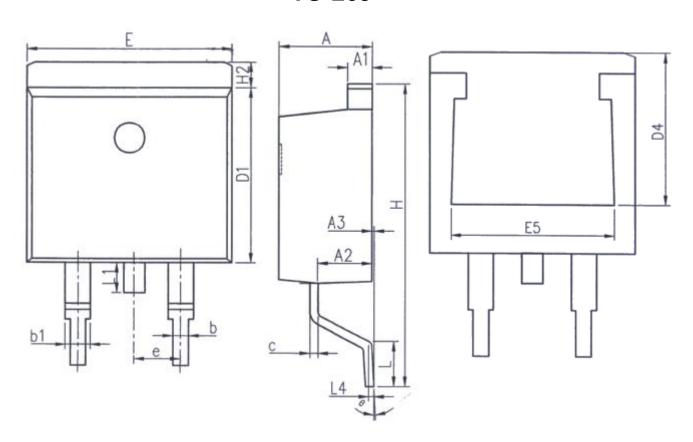






Unit: mm			l	Jnit: mm	1
Symbol	Min.	Max.	Symbol	Min.	Max.
E	9. 96	10. 36	L	12. 68	13. 28
Α	4. 50	4. 90	L1	2. 93	3. 13
A 1	2. 34	2. 74	Р	3. 03	3. 38
A2	0. 30	0.60	Р3	3. 15	3. 65
A4	2. 56	2. 96	F3	3. 15	3. 45
С	0.40	0. 65	G3	1. 25	1. 55
D	15. 57	16. 17	b1	1. 18	1. 43
H1	6. 70	OREF	b2	0. 70	0. 95
e	2. 54	4BSC			

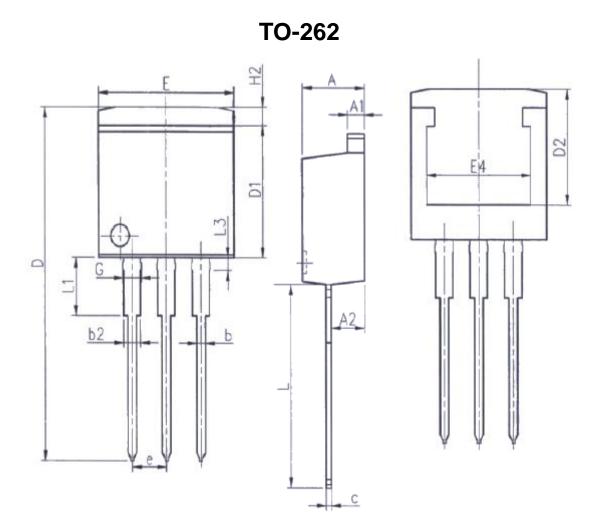
TO-263



Unit: mm					
Symbol	Min.	Max.			
Α	4. 37	4. 77			
A 1	1. 22	1. 42			
A2	2. 49	2. 89			
A3	0. 00	0. 25			
b	0. 70	0. 96			
b1	1. 17	1. 47			
С	0. 30	0. 53			
D1	8. 50	8. 90			
D4	6. 60	_			

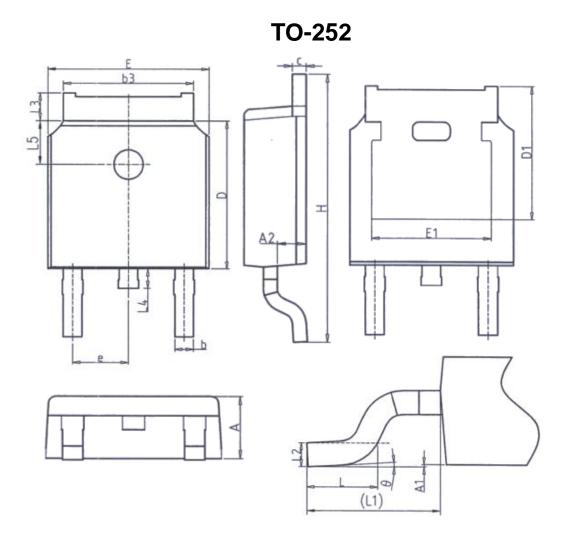
Unit: mm					
Symbol	Min.	Max.			
E	9.86	10.36			
E 5	7. 06	-			
e	2. 54BSC				
Н	14. 70	15. 50			
H2	1. 07	1. 47			
L	2.00	2. 60			
L1	1. 40	1. 70			
L4	0. 25BSC				
θ	0°	9°			





Unit: mm				
Symbol	Min.	Max.		
Α	4. 37	4. 77		
A1	1. 22	1. 42		
A2	2. 47	2. 87		
b	0. 70	0. 97		
b2	1. 17	1. 42		
С	0. 28	0.53		
D	23. 20	24. 02		
D1	8. 38	8. 90		
D2	6. 00	-		

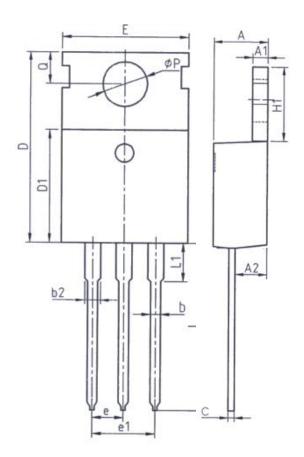
Unit: mm					
Symbol	Min.	Max.			
E	9. 90	10. 39			
E4	7. 30	-			
е	2. 54BSC				
G	1. 25	1.50			
H2	-	1. 31			
L	13. 34	14. 10			
L1	3. 30	4. 06			
L3	0. 95	1. 15			

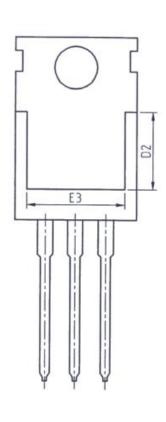


Unit: mm					
Symbol	Min.	Max.			
Α	2. 20	2. 40			
A1	0.00	0. 20			
A2	0. 97	1.17			
b	0. 68	0. 90			
b3	5. 20	5. 50			
С	0. 43	0. 63			
D	5. 98	6. 22			
D1	5. 30REF				
E	6. 40	6. 80			
E1	4. 63	_			

Unit: mm					
Symbol	Min.	Max.			
е	2. 28	6BSC			
Н	9. 40	10.50			
L	1. 38	1. 75			
L1	2. 90REF				
L2	0. 51	IBSC			
L3	0.88	1. 28			
L4	_	1.00			
L5	1. 65	1. 95			
θ	0°	8°			

TO-220

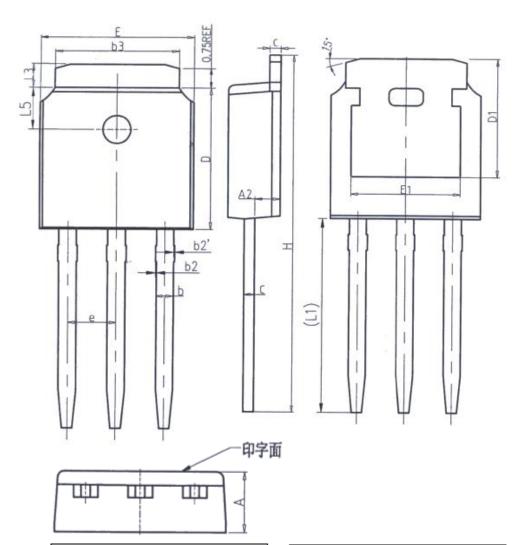




Unit: mm				
Symbol	Min.	Max.		
Α	4. 37	4. 77		
A1	1. 25	1. 45		
A2	2. 20	2. 60		
ь	0. 70	0. 95		
b2	1. 17	1. 47		
С	0. 40	0. 65		
D	15. 10	16. 10		
D1	8. 80	9. 40		
D2	5. 50	_		

Unit: mm			
Symbol	Min.	Max.	
E	9. 70	10. 30	
E3	7. 00	ı	
е	2. 54BSC		
e1	5. 08BSC		
H1	6. 25	6. 85	
L	12. 75	13.80	
L1	ı	3. 40	
Р	3. 40	3. 80	
Q	2. 60	3. 00	

TO-251



Unit: mm			
Symbol	Min.	Max.	
Α	2. 20	2. 40	
A2	0. 97	1. 17	
b	0. 68	0.90	
b2	0.00	0.10	
b2′	0.00	0.10	
b3	5. 20	5. 50	
С	0. 43	0. 63	
D	5. 98	6. 22	

Unit: mm			
Symbol	Min.	Max.	
D1	5. 30REF		
E	6. 40	6. 80	
E1	4. 63	-	
е	2. 286BSC		
Н	16. 22	16. 82	
L1	9. 15	9. 65	
L3	0.88	1. 28	
L5	1. 65	1. 95	



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